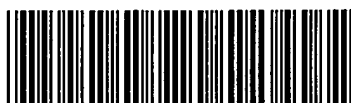


Search Notes



Application/Control No.

10/075,035

Examiner

Hien Tran

Applicant(s)/Patent under Reexamination

LIU ET AL.

Art Unit

1764

SEARCHED

Class	Subclass	Date	Examiner
422	171, 177 180	6/05	HT
↓		↓	↓
55	385.3, 482-484		
↓	499, 521 523-525		
↓	dig. 10, dig. 30		
↓	dig. 28		
60	311	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
Inv's names search, East image cl/sub search, ckt. related appl's 09/522, 152 & 09/851, 300	6/05 ↓	HT ↓